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FOR IMMEDIATE RELEASE

XRF Glass Panel Sampling Tool for CIGS and CdTe PV Panel Film Composition and Thickness Measurement

HOLBROOK, NY - Solar Metrology, a global provider of X-Ray Fluorescence (XRF) analysis tools, expands its portfolio of System SMX thin film composition and thickness measurement systems for CIGS and CdTe photovoltaic depositions with the addition of model **SMX-FPV** (Full Panel View).

SMX-FPV enables near-line film composition and thickness control of CIGS and CdTe film stacks. It has a full (600 x 1200 mm) lateral X-Y range of measurement and is designed for analysis of rigid glass substrates.

SMX-FPV provides process control of active, contact and TCO layers. Detailed analysis of full photovoltaic panels is possible, including fast and repeatable Copper to Gallium ratio determination. Panel gradient analysis provides yield improvement and conversion efficiency gains in production.

Solar Metrology's **SMX Measurement System** is a production-ready suite of film thickness and composition analysis tools, ideally suited to research and process development, in-process monitoring and post-process quality control.

Solar Metrology is a global leader in the development and manufacture of high-performance X-Ray Fluorescence (XRF) analysis tools specifically engineered to meet the demanding thin film measurement requirements of the solar electric and renewable power industries.

Additional information about Solar Metrology can be found at <http://www.solarmetrology.com> or info@solarmetrology.com.